



# ISO1500 3kV<sub>RMS</sub>、基本絶縁、超小型パッケージのRS-485/RS-422トランシーバ

## 1 特長

- TIA/EIA-485-A の要件に準拠、または超える仕様
- 半二重トランシーバ
- 低 EMI、1Mbps のデータ・レート
- バス I/O 保護
  - ±16kV の HBM ESD
- 1.71V~5.5V の ロジック側電源 (V<sub>CC1</sub>)、4.5V~5.5V の バス側電源 (V<sub>CC2</sub>)
- 1/8 の単位負荷で、バス上に最大 256 のノード
- バスの開放、短絡、アイドルに対するフェイルセーフを備えたレシーバー
- 100kV/μs (標準値) の高い同相過渡耐性
- 拡張温度範囲: -40°C~+125°C
- 電源オンおよび電源オフ時にグリッチがなく、ホット・プラグイン可能
- 超小型の SSOP (DBQ-16) パッケージ
- 安全関連の認定
  - DIN VDE V 0884-11:2017-01 準拠で 4242V<sub>PK</sub> V<sub>IOTM</sub> および 566V<sub>PK</sub> V<sub>IORM</sub>
  - UL 1577 に準拠した絶縁耐圧: 3000V<sub>RMS</sub> (1 分間)
  - IEC 60950-1、IEC 62368-1、IEC 61010-1 認定
  - CQC、TUV、CSA 認定
  - VDE、UL、CQC、TUV 認定済み、CSA 承認待ち

## 2 アプリケーション

- 電気メータ
- 保護リレー
- ファクトリ・オートメーション / 制御
- HVAC システムおよびビルディング・オートメーション
- モータ・ドライブ

## 3 概要

ISO1500 デバイスは、ガルバニック絶縁された、TIA/EIA RS-485 および RS-422 アプリケーション用の差動ライン・トランシーバです。このデバイスは、3 チャンネルのデジタル・アイソレータと RS-485 トランシーバが、超小型の 16 ピン SSOP パッケージに搭載されています。このトランシーバのバス・ピンは、IEC ESD 接触放電および IEC EFT イベンツから保護されています。レシーバーの出力には、バス開放、短絡、アイドル条件に対してのフェイルセーフがあります。ISO1500 はソリューション・サイズが小さいため、他の統合絶縁 RS-485 ソリューションや、フォトカプラと非絶縁 RS-485 トランシーバを個別に実装する場合と比較して、必要な基板面積が大幅に削減されます。

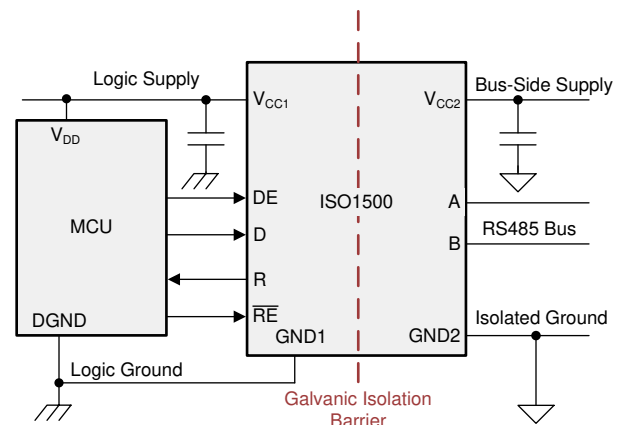
このデバイスは、長距離通信に使用されます。絶縁により通信ノード間のグランド・ループが遮断されるため、より広い同相電圧範囲に対応できます。各デバイスの対称型絶縁バリアは、バスライン・トランシーバとロジックレベル・インターフェイスとの間で、UL 1577 に従い、3000V<sub>RMS</sub> で 1 分間の絶縁を行うことがテスト済みです。

### 製品情報<sup>(1)</sup>

型番	パッケージ	本体サイズ(公称)
ISO1500	SSOP (16)	4.90mm×3.90mm

(1) 利用可能なすべてのパッケージについては、このデータシートの末尾にある注文情報を参照してください。

### 概略回路図



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## 4 改訂履歴

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Revision B (May 2019) から Revision C に変更	Page
• 「特長」セクションの認定関連情報を 変更	1
• Added footnote to Pin function table for NC pin	4
• Changed <a href="#">Insulation Specifications</a> table with test condition for VIOSM and qPD (Partial discharge)	7
• Changed certificate related info in <a href="#">Safety-Related Certifications</a> section	8

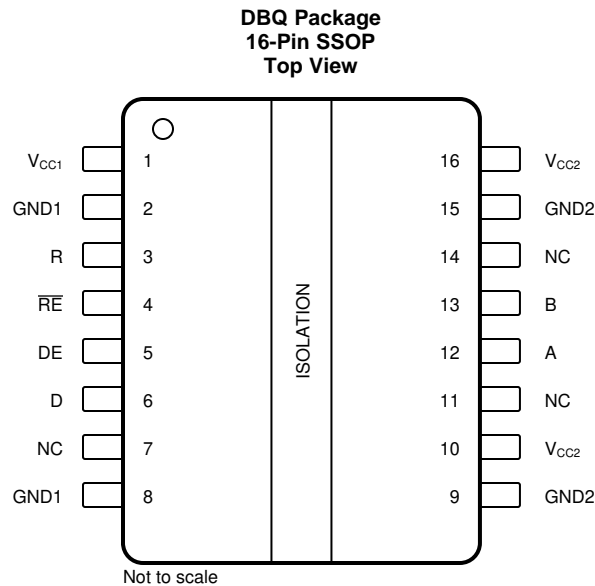
Revision A (December 2018) から Revision B に変更	Page
• 「特長」の一覧に HBM ESD を 追加	1

2018年9月発行のものから更新	Page
• デバイスのステータスを事前情報から量産データに 変更	1

## 5 概要 (続き)

ISO1500xデバイスは、サイド1において1.71V～5.5Vの電圧で動作できるため、デバイスを低電圧のFPGAやASICと接続できます。サイド2の電源電圧は4.5V～5.5Vです。このデバイスは、-40°C～+125°Cの広い動作時周囲温度に対応しています。

## 6 Pin Configuration and Functions



### Pin Functions

PIN		I/O	DESCRIPTION
NAME	NO.		
A	12	I/O	Transceiver noninverting input or output (I/O) on the bus side
B	13	I/O	Transceiver inverting input or output (I/O) on the bus side
D	6	I	Driver input
DE	5	I	Driver enable. This pin enables the driver output when high and disables the driver output when low or open.
GND1	2	—	Ground connection for V <sub>CC1</sub>
	8		
GND2	9	—	Ground connection for V <sub>CC2</sub>
	15		
NC <sup>(1)</sup>	7	—	No internal connection
	11		
	14		
R	3	O	Receiver output
$\overline{RE}$	4	I	Receiver enable. This pin disables the receiver output when high or open and enables the receiver output when low.
V <sub>CC1</sub>	1	—	Logic-side power supply
V <sub>CC2</sub>	10	—	Transceiver-side power supply. These pins are not connected internally and must be shorted externally on PCB.
	16		

(1) Device functionality is not affected if NC pins are connected to supply or ground on PCB

## 7 Specifications

### 7.1 Absolute Maximum Ratings

Over operating free-air temperature range (unless otherwise noted)<sup>(1)(2)</sup>

		MIN	MAX	UNIT
V <sub>CC1</sub>	Supply voltage, side 1	-0.5	6	V
V <sub>CC2</sub>	Supply voltage, side 2	-0.5	6	V
V <sub>IO</sub>	Logic voltage level (D, DE, $\overline{RE}$ , R)	-0.5	V <sub>CC1</sub> +0.5 <sup>(3)</sup>	V
I <sub>O</sub>	Output current on R pin	-15	15	mA
V <sub>BUS</sub>	Voltage on bus pins (A, B, Y, Z w.r.t GND2)	-18	18	V
T <sub>J</sub>	Junction temperature	-40	150	°C
T <sub>STG</sub>	Storage temperature	-65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltage values except differential I/O bus voltages are with respect to the local ground terminal (GND1 or GND2) and are peak voltage values.
- (3) Maximum voltage must not exceed 6 V

### 7.2 ESD Ratings

			VALUE	UNIT
V <sub>(ESD)</sub>	Electrostatic discharge Human body model (HBM), per ANSI/ESDA/JEDEC JS-001	All pins except bus pins <sup>(1)</sup>	±4000	V
		Bus terminals to GND2 <sup>(1)</sup>	±16000	V
	Electrostatic discharge Charged device model (CDM), per JEDEC specification JESD22-C101	All pins <sup>(2)</sup>	±1500	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

### 7.3 Recommended Operating Conditions

		MIN	MAX	UNIT
V <sub>CC1</sub>	Supply Voltage, Side 1, 1.8-V operation	1.71	1.89	V
	Supply Voltage, Side 1, 2.5-V, 3.3-V and 5.5-V operation	2.25	5.5	V
V <sub>CC2</sub>	Supply Voltage, Side 2	4.5	5.5	V
V <sub>I</sub>	Common mode voltage at any bus terminal: A or B	-7	12	V
V <sub>IH</sub>	High-level input voltage (D, DE, $\overline{RE}$ inputs)	0.7*V <sub>CC1</sub>	V <sub>CC1</sub>	V
V <sub>IL</sub>	Low-level input voltage (D, DE, $\overline{RE}$ inputs)	0	0.3*V <sub>CC1</sub>	V
V <sub>ID</sub>	Differential input voltage	-12	12	V
I <sub>O</sub>	Output current, Driver	-60	60	mA
I <sub>OR</sub>	Output current, Receiver	-4	4	mA
R <sub>L</sub>	Differential load resistance	54		Ω
1/t <sub>UI</sub>	Signaling rate		1	Mbps
T <sub>A</sub>	Operating ambient temperature	-40	125	°C

### 7.4 Thermal Information

THERMAL METRIC <sup>(1)</sup>		ISO1500	UNIT
		DBQ (SSOP)	
		16 PINS	
R <sub>θJA</sub>	Junction-to-ambient thermal resistance	112.7	°C/W
R <sub>θJC(top)</sub>	Junction-to-case (top) thermal resistance	57.2	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

**Thermal Information (continued)**

THERMAL METRIC <sup>(1)</sup>		ISO1500	UNIT
		DBQ (SSOP)	
		16 PINS	
$R_{\theta JB}$	Junction-to-board thermal resistance	64.0	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	32.1	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	63.7	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	--	°C/W

**7.5 Power Ratings**

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$P_D$	Maximum power dissipation (both sides)	$V_{CC1} = V_{CC2} = 5.5 \text{ V}$ , $T_A = 125^\circ\text{C}$ , $T_J = 150^\circ\text{C}$ , A-B load = $54 \Omega \parallel 50\text{pF}$ , Load on $R = 15\text{pF}$ Input a 500kHz 50% duty cycle square wave to D pin with $V_{DE} = V_{CC1}$ , $\overline{V_{RE}} = \text{GND1}$			278	mW
$P_{D1}$	Maximum power dissipation (side-1)				28	mW
$P_{D2}$	Maximum power dissipation (side-2)				250	mW

## 7.6 Insulation Specifications

PARAMETER		TEST CONDITIONS	SPECIFICATIONS	UNIT
			DBQ-16	
IEC 60664-1				
CLR	External clearance <sup>(1)</sup>	Side 1 to side 2 distance through air	>3.7	mm
CPG	External creepage <sup>(1)</sup>	Side 1 to side 2 distance across package surface	>3.7	mm
DTI	Distance through the insulation	Minimum internal gap (internal clearance)	>17	μm
CTI	Comparative tracking index	IEC 60112; UL 746A	>600	V
	Material Group	According to IEC 60664-1	I	
	Overvoltage category	Rated mains voltage ≤ 300 V <sub>RMS</sub>	I-III	
DIN VDE V 0884-11:2017-01 <sup>(2)</sup>				
V <sub>IORM</sub>	Maximum repetitive peak isolation voltage	AC voltage (bipolar)	566	V <sub>PK</sub>
V <sub>IOWM</sub>	Maximum isolation working voltage	AC voltage (sine wave); time-dependent dielectric breakdown (TDDb) test;	400	V <sub>RMS</sub>
		DC voltage	566	V <sub>DC</sub>
V <sub>IOTM</sub>	Maximum transient isolation voltage	V <sub>TEST</sub> = V <sub>IOTM</sub> , t = 60 s (qualification); V <sub>TEST</sub> = 1.2 × V <sub>IOTM</sub> , t = 1 s (100% production)	4242	V <sub>PK</sub>
V <sub>IOSM</sub>	Maximum surge isolation voltage ISO1500 <sup>(3)</sup>	Test method per IEC 62368-1, 1.2/50 μs waveform, V <sub>TEST</sub> = 10000 V <sub>PK</sub> (qualification)	4000	V <sub>PK</sub>
q <sub>pd</sub>	Apparent charge <sup>(4)</sup>	Method a: After I/O safety test subgroup 2/3, V <sub>ini</sub> = V <sub>IOTM</sub> , t <sub>ini</sub> = 60 s; V <sub>pd(m)</sub> = 1.2 × V <sub>IORM</sub> , t <sub>m</sub> = 10 s	≤ 5	pC
		Method a: After environmental tests subgroup 1, V <sub>ini</sub> = V <sub>IOTM</sub> , t <sub>ini</sub> = 60 s; V <sub>pd(m)</sub> = 1.6 × V <sub>IORM</sub> , t <sub>m</sub> = 10 s	≤ 5	
		Method b1: At routine test (100% production) and preconditioning (type test), V <sub>ini</sub> = V <sub>IOTM</sub> , t <sub>ini</sub> = 1 s; V <sub>pd(m)</sub> = 1.875 × V <sub>IORM</sub> , t <sub>m</sub> = 1 s	≤ 5	
C <sub>IO</sub>	Barrier capacitance, input to output <sup>(5)</sup>	V <sub>IO</sub> = 0.4 × sin (2 πft), f = 1 MHz	~1	pF
R <sub>IO</sub>	Insulation resistance, input to output <sup>(5)</sup>	V <sub>IO</sub> = 500 V, T <sub>A</sub> = 25°C	> 10 <sup>12</sup>	Ω
		V <sub>IO</sub> = 500 V, 100°C ≤ T <sub>A</sub> ≤ 150°C	> 10 <sup>11</sup>	
		V <sub>IO</sub> = 500 V at T <sub>S</sub> = 150°C	> 10 <sup>9</sup>	
	Pollution degree		2	
	Climatic category		40/125/21	
UL 1577				
V <sub>ISO</sub>	Withstand isolation voltage	V <sub>TEST</sub> = V <sub>ISO</sub> , t = 60 s (qualification); V <sub>TEST</sub> = 1.2 × V <sub>ISO</sub> , t = 1 s (100% production)	3000	V <sub>RMS</sub>

- (1) Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed-circuit board do not reduce this distance. Creepage and clearance on a printed-circuit board become equal in certain cases. Techniques such as inserting grooves, ribs, or both on a printed circuit board are used to help increase these specifications.
- (2) ISO1500 is suitable for safe *electrical insulation* within the safety ratings. Compliance with the safety ratings shall be ensured by means of suitable protective circuits.
- (3) Testing is carried out in air or oil to determine the intrinsic surge immunity of the isolation barrier.
- (4) Apparent charge is electrical discharge caused by a partial discharge (pd).
- (5) All pins on each side of the barrier tied together creating a two-pin device.

## 7.7 Safety-Related Certifications

VDE	CSA	UL	CQC	TUV
Certified according to DIN VDE V 0884-11:2017- 01	Plan to certify according to IEC 60950-1, IEC 62368-1	Recognized under UL 1577 Component Recognition Program	Certified according to GB4943.1-2011	Certified according to EN 61010-1:2010/A1:2019, EN 60950-1:2006/A2:2013 and EN 62368-1:2014
Maximum transient isolation voltage, 4242 V <sub>PK</sub> ; Maximum repetitive peak isolation voltage, 566 V <sub>PK</sub> ; Maximum surge isolation voltage, 4000 V <sub>PK</sub>	CSA 60950-1-07+A1+A2 and IEC 60950-1 2nd Ed., for pollution degree 2, material group I: 370 V <sub>RMS</sub>	Single protection, 3000 V <sub>RMS</sub>	Basic insulation, Altitude ≤ 5000 m, Tropical Climate, 400 V <sub>RMS</sub> maximum working voltage	EN 61010-1:2010/A1:2019, 300 VRMS basic isolation ----- EN 60950-1:2006/A2:2013 and EN 62368-1:2014, 400 VRMS basic isolation
Certificate number: 40040142	Certificate planned	File number: E181974	Certificate number: CQC18001199097	Client ID number: 77311

## 7.8 Safety Limiting Values

Safety limiting<sup>(1)</sup> intends to minimize potential damage to the isolation barrier upon failure of input or output circuitry.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>DBQ-16 PACKAGE</b>					
I <sub>S</sub>	Safety input, output, or supply current	R <sub>θJA</sub> = 67.9°C/W, V <sub>I</sub> = 5.5 V, T <sub>J</sub> = 150°C, T <sub>A</sub> = 25°C, see <a href="#">1</a>		201	mA
		R <sub>θJA</sub> = 67.9°C/W, V <sub>I</sub> = 3.6 V, T <sub>J</sub> = 150°C, T <sub>A</sub> = 25°C, see <a href="#">1</a>		308	
		R <sub>θJA</sub> = 67.9°C/W, V <sub>I</sub> = 2.75 V, T <sub>J</sub> = 150°C, T <sub>A</sub> = 25°C, see <a href="#">1</a>		403	
		R <sub>θJA</sub> = 67.9°C/W, V <sub>I</sub> = 1.89 V, T <sub>J</sub> = 150°C, T <sub>A</sub> = 25°C, see <a href="#">1</a>		586	
P <sub>S</sub>	Safety input, output, or total power	R <sub>θJA</sub> = 67.9°C/W, T <sub>J</sub> = 150°C, T <sub>A</sub> = 25°C, see <a href="#">2</a>		1105	mW
T <sub>S</sub>	Maximum safety temperature			150	°C

- (1) The maximum safety temperature, T<sub>S</sub>, has the same value as the maximum junction temperature, T<sub>J</sub>, specified for the device. The I<sub>S</sub> and P<sub>S</sub> parameters represent the safety current and safety power respectively. The maximum limits of I<sub>S</sub> and P<sub>S</sub> should not be exceeded. These limits vary with the ambient temperature, T<sub>A</sub>.

The junction-to-air thermal resistance, R<sub>θJA</sub>, in the table is that of a device installed on a high-K test board for leaded surface-mount packages. Use these equations to calculate the value for each parameter:

T<sub>J</sub> = T<sub>A</sub> + R<sub>θJA</sub> × P, where P is the power dissipated in the device.

T<sub>J(max)</sub> = T<sub>S</sub> = T<sub>A</sub> + R<sub>θJA</sub> × P<sub>S</sub>, where T<sub>J(max)</sub> is the maximum allowed junction temperature.

P<sub>S</sub> = I<sub>S</sub> × V<sub>I</sub>, where V<sub>I</sub> is the maximum input voltage.



## 7.9 Electrical Characteristics: Driver

Typical specs are at  $V_{CC1}=3.3V$ ,  $V_{CC2}=5V$ ,  $T_A=27^{\circ}C$  (Min/Max specs are over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$ V_{OD} $	Open circuit voltage, unloaded bus, $4.5V \leq V_{CC2} \leq 5.5V$	1.5	4.3	$V_{CC2}$	V
	$R_L = 60\Omega$ , $-7V \leq V_{TEST} \leq 12V$ , $4.5V < V_{CC2} < 5.5V$ (see <a href="#">Figure 19</a> )	1.5	2.5		V
	$R_L = 100\Omega$ (see <a href="#">Figure 20</a> ), RS-422 load	2	2.9		V
	$R_L = 54\Omega$ (see <a href="#">Figure 20</a> ), RS-485 load, $4.5V < V_{CC2} < 5.5V$	1.5	2.5		V
$\Delta V_{OD} $	Change in differential output voltage between two states	$R_L = 54\Omega$ or $R_L = 100\Omega$ , see <a href="#">Figure 20</a>		50	mV
$V_{OC}$	Common-mode output voltage	$R_L = 54\Omega$ or $R_L = 100\Omega$ , see <a href="#">Figure 20</a>	$0.5 \times V_{CC2}$	3	V
$\Delta V_{OC(SS)}$	change in steady-state common-mode output voltage between two states	$R_L = 54\Omega$ or $R_L = 100\Omega$ , see <a href="#">Figure 20</a>		50	mV
$V_{OC(PP)}$	Peak-to-peak common-mode output voltage	$R_L = 54\Omega$ or $R_L = 100\Omega$ , see <a href="#">Figure 20</a>	300		mV
$I_{OS}$	Short-circuit output current	$V_D = V_{CC1}$ or $V_D = V_{GND1}$ , $V_{DE} = V_{CC1}$ , $-7V \leq V_O \leq 12V$ , see <a href="#">Figure 28</a>	-175	175	mA
$I_i$	Input current	$V_D$ and $V_{DE} = 0V$ or $V_D$ and $V_{DE} = V_{CC1}$	-10	10	$\mu A$
CMTI	Common-mode transient immunity	$V_D = V_{CC1}$ or $GND1$ , $V_{CM} = 1200V$ , See <a href="#">Figure 22</a>	85	100	kV/ $\mu s$

## 7.10 Electrical Characteristics: Receiver

Typical specs are at  $V_{CC1}=3.3V$ ,  $V_{CC2}=5V$ ,  $T_A=27^{\circ}C$  (Min/Max are over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_{i1}$	Bus input current	$V_{DE} = 0V$ , $V_{CC2} = 0V$ or $V_{CC2} = 5.5V$ , One bus input at $-7V$ or $12V$ , other input at $0V$		100	$\mu A$
$V_{TH+}$	Positive-going input threshold voltage	$-7V \leq$ Common mode voltage on bus terminals $\leq$ $12V$	See <sup>(1)</sup>	-100	mV
$V_{TH-}$	Negative-going input threshold voltage	$-7V \leq$ Common mode voltage on bus terminals $\leq$ $12V$	-200	-145	See <sup>(1)</sup> mV
$V_{hys}$	Input hysteresis ( $V_{TH+} - V_{TH-}$ )	$-7V \leq$ Common mode voltage on bus terminals $\leq$ $12V$	20	45	mV
$V_{OH}$	Output high voltage on the R pin	$V_{CC1}=5V \pm 10\%$ , $I_{OH} = -4mA$ , $V_{ID} = 200mV$	$V_{CC1} - 0.4$		V
		$V_{CC1}=3.3V \pm 10\%$ , $I_{OH} = -2mA$ , $V_{ID} = 200mV$	$V_{CC1} - 0.3$		V
		$V_{CC1}=2.5V \pm 10\%$ , $1.8V \pm 5\%$ , $I_{OH} = -1mA$ , $V_{ID} =$ $200mV$	$V_{CC1} - 0.2$		V
$V_{OL}$	Output low voltage on the R pin	$V_{CC1}=5V \pm 10\%$ , $I_{OL} = 4mA$ , $V_{ID} = -200mV$		0.4	V
		$V_{CC1}=3.3V \pm 10\%$ , $I_{OL} = 2mA$ , $V_{ID} = -200mV$		0.3	V
		$V_{CC1}=2.5V \pm 10\%$ , $1.8V \pm 5\%$ , $I_{OL} = 1mA$ , $V_{ID} =$ $-200mV$		0.2	V
$I_{OZ}$	Output high-impedance current on the R pin	$V_R = 0V$ or $V_R = V_{CC1}$ , $\overline{V_{RE}} = V_{CC1}$	-1	1	$\mu A$
$I_i$	Input current on the $\overline{RE}$ pin	$\overline{V_{RE}} = 0V$ or $\overline{V_{RE}} = V_{CC1}$	-10	10	$\mu A$
CMTI	Common-mode transient immunity	$V_{ID} = 1.5V$ or $-1.5V$ , $V_{CM} = 1200V$ , See <a href="#">Figure 22</a>	85	100	kV/ $\mu s$

(1) Under any specific conditions,  $V_{TH+}$  is ensured to be at least  $V_{hys}$  higher than  $V_{TH-}$ .

## 7.11 Supply Current Characteristics: Side 1( $I_{CC1}$ )

Bus loaded or unloaded (over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>DRIVER ENABLED, RECEIVER DISABLED</b>					
Logic-side supply current	$V_D = V_{CC1}$ , $V_{CC1} = 5\text{ V} \pm 10\%$		2.6	4.4	mA
Logic-side supply current	$V_D = V_{CC1}$ , $V_{CC1} = 3.3\text{ V} \pm 10\%$		2.6	4.4	mA
Logic-side supply current	$D = 1\text{Mbps}$ square wave with 50% duty cycle, $V_{CC1} = 5\text{ V} \pm 10\%$		3.2	5.1	mA
Logic-side supply current	$D = 1\text{Mbps}$ square wave with 50% duty cycle, $V_{CC1} = 3.3\text{ V} \pm 10\%$		3.2	5.1	mA
<b>DRIVER ENABLED, RECEIVER ENABLED</b>					
Logic-side supply current	$\overline{V_{RE}} = V_{GND1}$ , $V_D = V_{CC1}$ , $V_{CC1} = 5\text{ V} \pm 10\%$		2.6	4.4	mA
Logic-side supply current	$\overline{V_{RE}} = V_{GND1}$ , $V_D = V_{CC1}$ , $V_{CC1} = 3.3\text{ V} \pm 10\%$		2.6	4.4	mA
Logic-side supply current	$\overline{V_{RE}} = V_{GND1}$ , $D = 1\text{Mbps}$ square wave with 50% duty cycle, $V_{CC1} = 5\text{ V} \pm 10\%$ , $C_{L(R)}^{(1)} = 15\text{ pF}$		3.4	5.2	mA
Logic-side supply current	$\overline{V_{RE}} = V_{GND1}$ , $D = 1\text{Mbps}$ square wave with 50% duty cycle, $V_{CC1} = 3.3\text{ V} \pm 10\%$ , $C_{L(R)}^{(1)} = 15\text{ pF}$		3.2	5.2	mA
<b>DRIVER DISABLED, RECEIVER ENABLED</b>					
Logic-side supply current	$V_{(A-B)} \geq 200\text{ mV}$ , $V_D = V_{CC1}$ , $V_{CC1} = 5\text{ V} \pm 10\%$		1.5	3.1	mA
Logic-side supply current	$V_{(A-B)} \geq 200\text{ mV}$ , $V_D = V_{CC1}$ , $V_{CC1} = 3.3\text{ V} \pm 10\%$		1.5	3.1	mA
Logic-side supply current	$(A-B) = 1\text{Mbps}$ square wave with 50% duty cycle, $V_D = V_{CC1}$ , $V_{CC1} = 5\text{ V} \pm 10\%$ , $C_{L(R)}^{(1)} = 15\text{ pF}$		1.7	3.2	mA
Logic-side supply current	$(A-B) = 1\text{Mbps}$ square wave with 50% duty cycle, $V_D = V_{CC1}$ , $V_{CC1} = 3.3\text{ V} \pm 10\%$ , $C_{L(R)}^{(1)} = 15\text{ pF}$		1.7	3.2	mA
<b>DRIVER DISABLED, RECEIVER DISABLED</b>					
Logic-side supply current	$V_{DE} = V_{GND1}$ , $V_D = V_{CC1}$ , $V_{CC1} = 5\text{ V} \pm 10\%$		1.5	3.1	mA
Logic-side supply current	$V_{DE} = V_{GND1}$ , $V_D = V_{CC1}$ , $V_{CC1} = 3.3\text{ V} \pm 10\%$		1.5	3.1	mA

(1)  $C_{L(R)}$  is the load capacitance on the R pin.

## 7.12 Supply Current Characteristics: Side 2( $I_{CC2}$ )

$\overline{V_{RE}} = V_{GND1}$  or  $\overline{V_{RE}} = V_{CC1}$  (over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>DRIVER ENABLED, BUS UNLOADED</b>					
Bus-side supply current	$V_D = V_{CC1}$ , $V_{CC2} = 5\text{ V} \pm 10\%$		2.5	4.4	mA
<b>DRIVER ENABLED, BUS LOADED</b>					
Bus-side supply current	$V_D = V_{CC1}$ , $R_L = 54\ \Omega$ , $V_{CC2} = 5\text{ V} \pm 10\%$		52	70	mA
Bus-side supply current	$D = 1\text{Mbps}$ square wave with 50% duty cycle, $R_L = 54\ \Omega$ , $C_L = 50\text{ pF}$ , $V_{CC2} = 5\text{ V} \pm 10\%$		60	80	mA
<b>DRIVER DISABLED, BUS LOADED OR UNLOADED</b>					
Bus-side supply current	$V_D = V_{CC1}$ , $V_{CC2} = 5\text{ V} \pm 10\%$		2.4	3.9	mA

### 7.13 Switching Characteristics: Driver

Typical specs are at  $V_{CC1}=3.3V$ ,  $V_{CC2}=5V$ ,  $T_A=27^{\circ}C$  (Min/Max specs over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>1Mbps DEVICE</b>					
$t_r, t_f$	Differential output rise time and fall time $R_L = 54 \Omega$ , $C_L = 50 \text{ pF}$ , see <a href="#">Figure 21</a>		210	300	ns
$t_{PHL}, t_{PLH}$	Propagation delay $R_L = 54 \Omega$ , $C_L = 50 \text{ pF}$ , see <a href="#">Figure 21</a>		210	300	ns
PWD	Pulse width distortion <sup>(1)</sup> , $ t_{PHL} - t_{PLH} $ $R_L = 54 \Omega$ , $C_L = 50 \text{ pF}$ , see <a href="#">Figure 21</a>		3	30	ns
$t_{PHZ}, t_{PLZ}$	Disable time See <a href="#">Figure 23</a> , and <a href="#">Figure 24</a>		160	250	ns
$t_{PZH}, t_{PZL}$	Enable time See <a href="#">Figure 23</a> , and <a href="#">Figure 24</a>		200	400	ns

(1) Also known as pulse skew.

### 7.14 Switching Characteristics: Receiver

Typical specs are at  $V_{CC1}=3.3V$ ,  $V_{CC2}=5V$ ,  $T_A=27^{\circ}C$  (Min/Max are over recommended operating conditions unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<b>1Mbps DEVICE</b>					
$t_r, t_f$	Differential output rise time and fall time $C_L = 15 \text{ pF}$ , see <a href="#">Figure 25</a>		2.4	4	ns
$t_{PHL}, t_{PLH}$	Propagation delay $C_L = 15 \text{ pF}$ , see <a href="#">Figure 25</a>		120	180	ns
PWD	Pulse width distortion <sup>(1)</sup> , $ t_{PHL} - t_{PLH} $ $C_L = 15 \text{ pF}$ , see <a href="#">Figure 25</a>		5	20	ns
$t_{PHZ}, t_{PLZ}$	Disable time See <a href="#">Figure 26</a> and <a href="#">Figure 27</a>		11	30	ns
$t_{PZH}, t_{PZL}$	Enable time See <a href="#">Figure 26</a> and <a href="#">Figure 27</a>		7	20	ns

(1) Also known as pulse skew.

### 7.15 Insulation Characteristics Curves

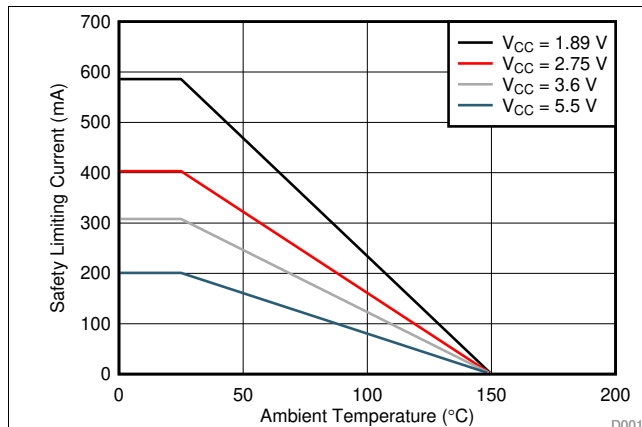


Figure 1. Thermal Derating Curve for Limiting Current per VDE

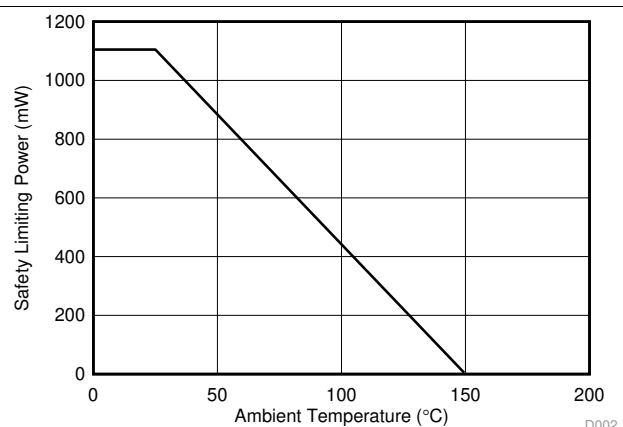


Figure 2. Thermal Derating Curve for Limiting Power per VDE

## 7.16 Typical Characteristics

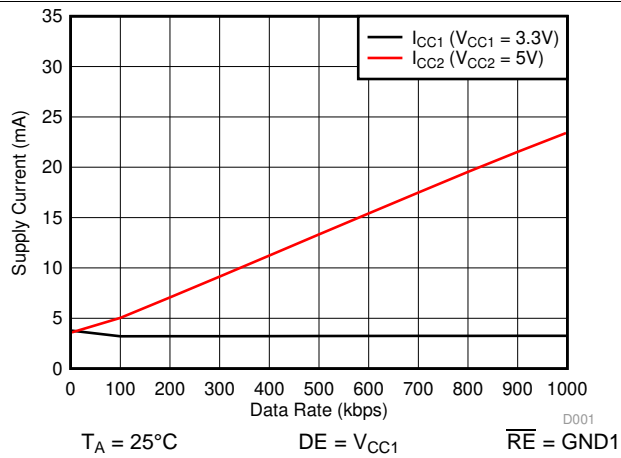


Figure 3. Supply Current Vs Data Rate- No Load

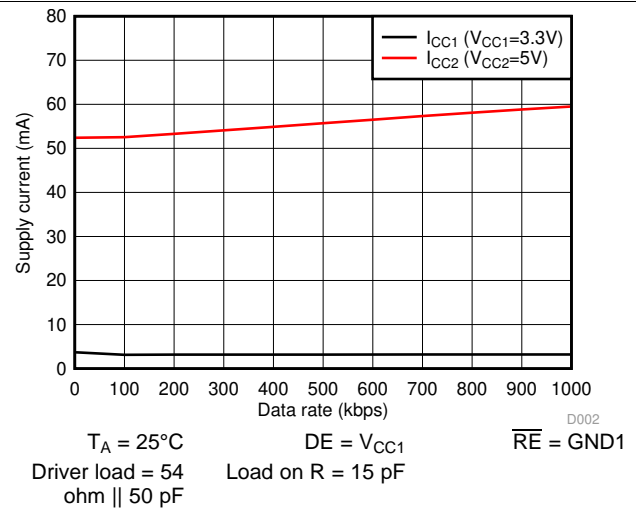


Figure 4. Supply Current Vs Data Rate- with 54 Ω || 50 pf Load

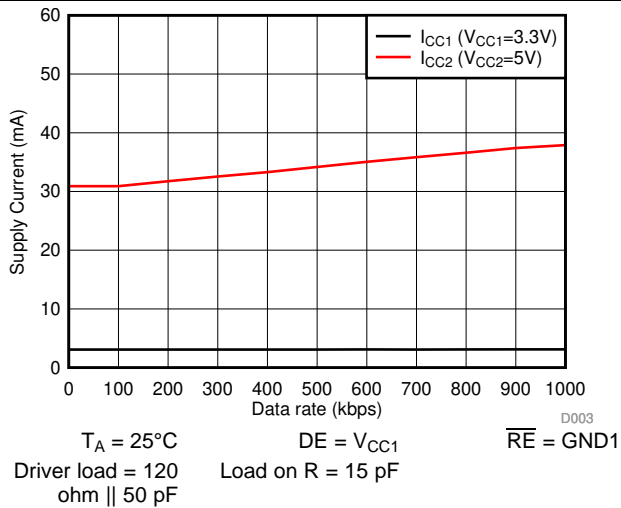


Figure 5. Supply Current Vs Data Rate - with 120 Ω || 50 pf Load

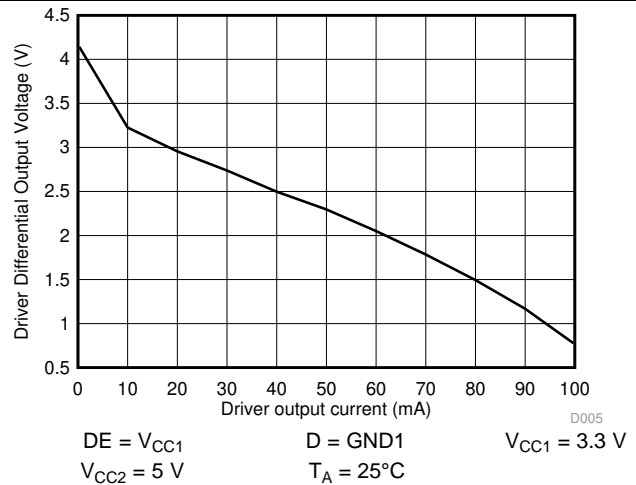


Figure 6. Driver Differential Output Voltage Vs Driver Output Current

## Typical Characteristics (continued)

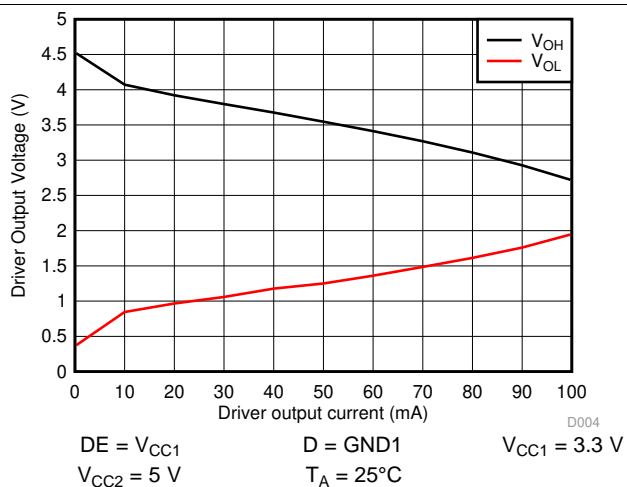


图 7. Driver Output Voltage Vs Driver Output Current

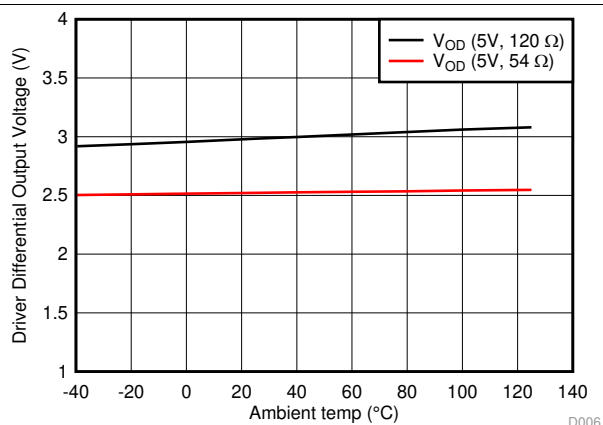


图 8. Driver Differential Output Voltage Vs Temperature

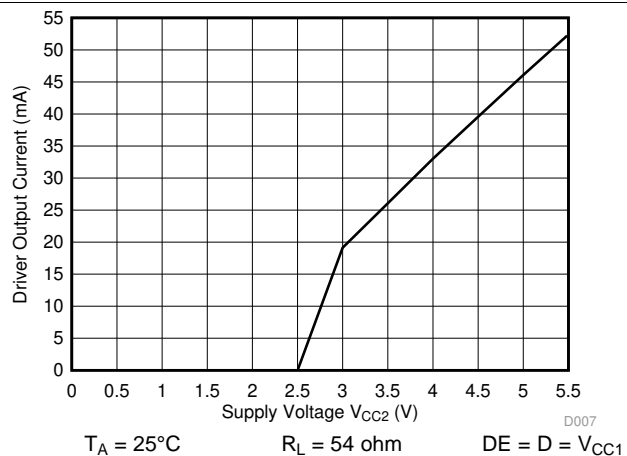


图 9. Driver Output Current Vs Supply Voltage ( $V_{CC2}$ )

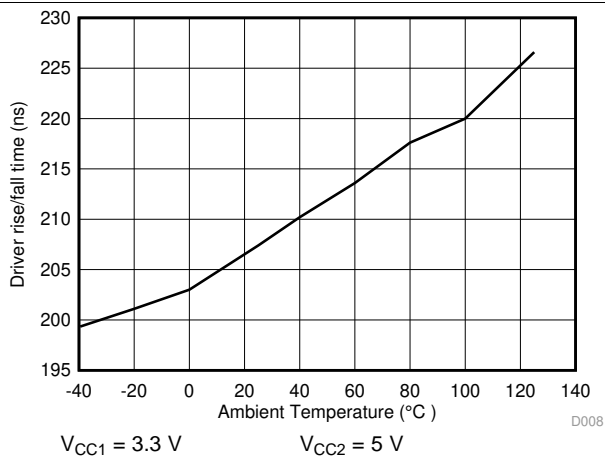


图 10. Driver rise/fall time vs Temperature

## Typical Characteristics (continued)

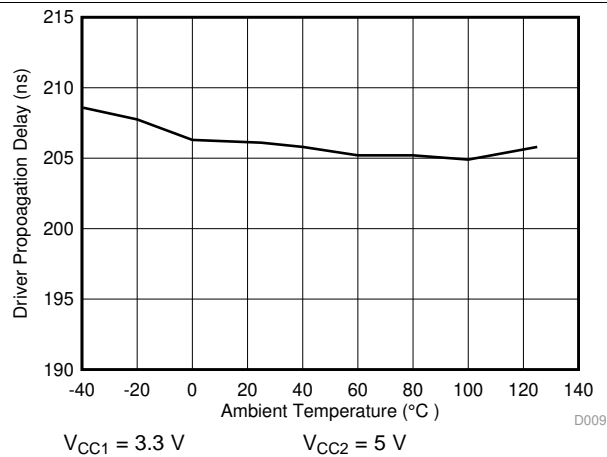


图 11. Driver Propagation Delay vs Temperature

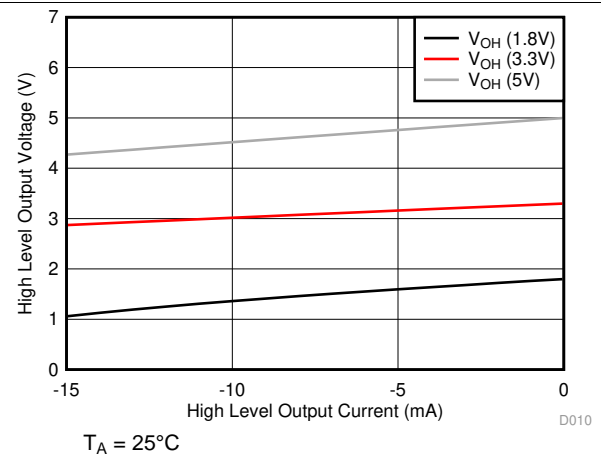


图 12. Receiver Buffer High Level Output Voltage Vs High Level Output Current

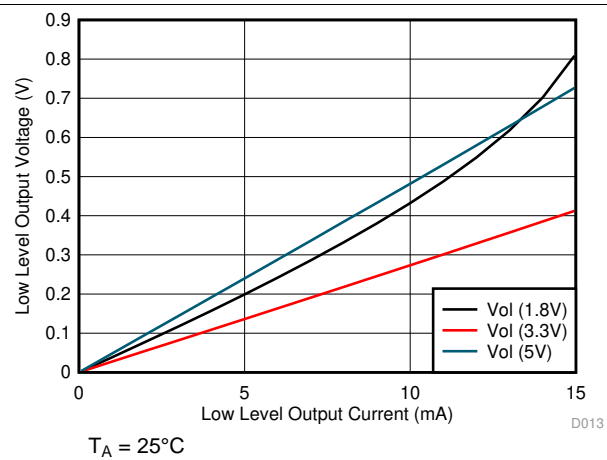


图 13. Receiver Buffer Low Level Output Voltage Vs Low Level Output Current

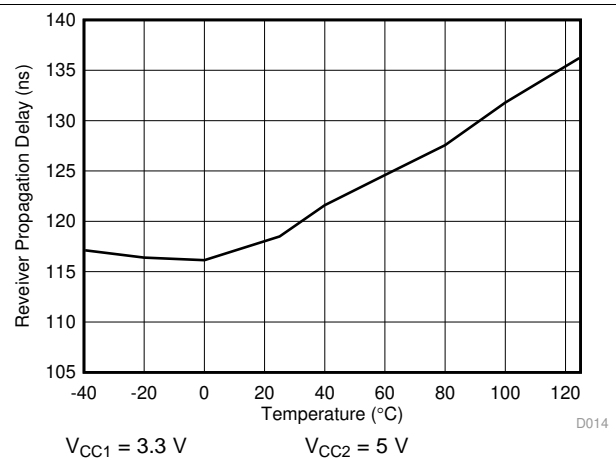
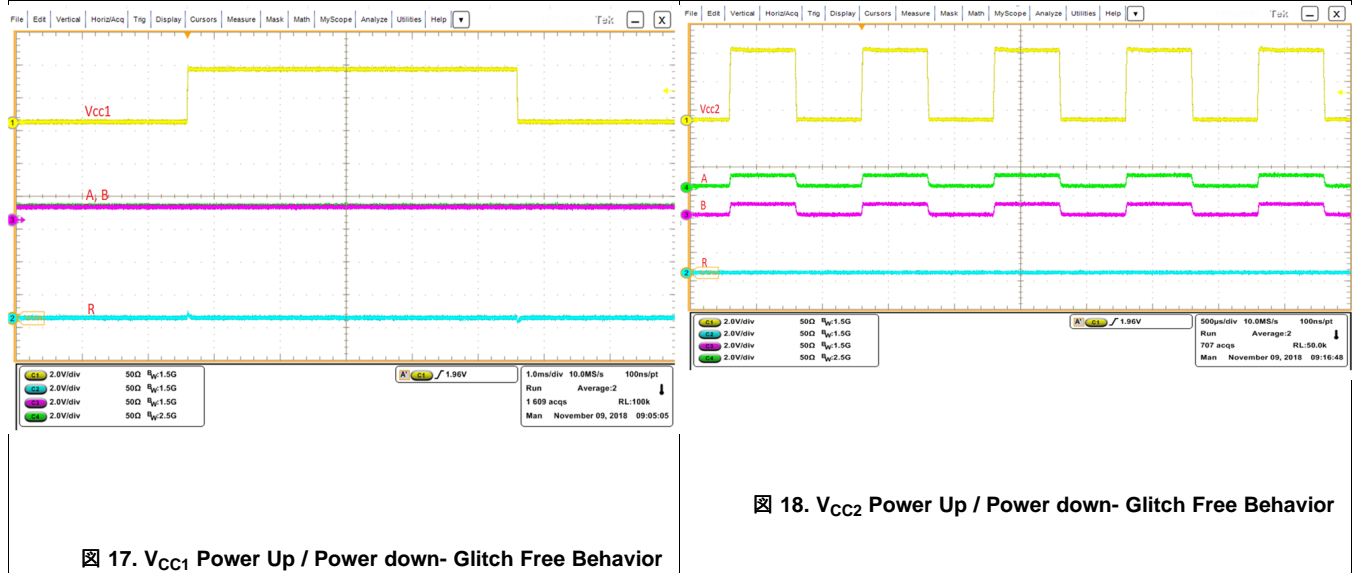
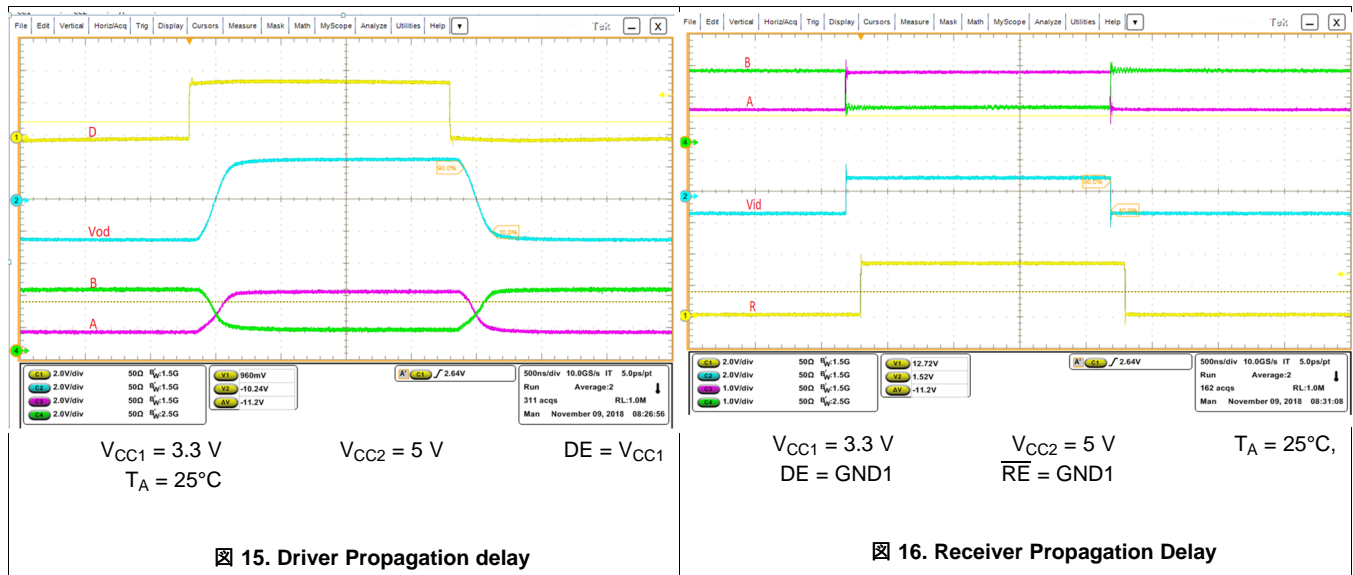


图 14. Receiver Propagation Delay Vs Temperature

## Typical Characteristics (continued)



## 8 Parameter Measurement Information

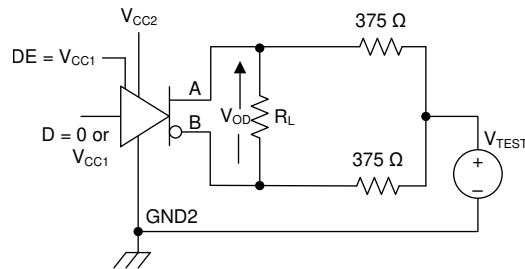
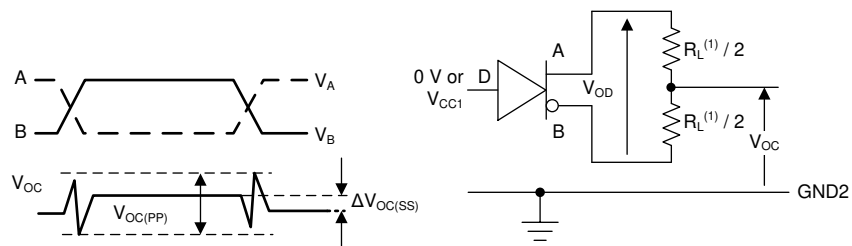
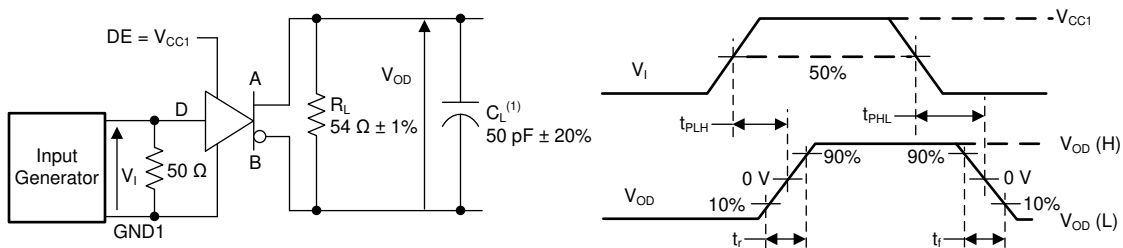


图 19. Driver Voltages



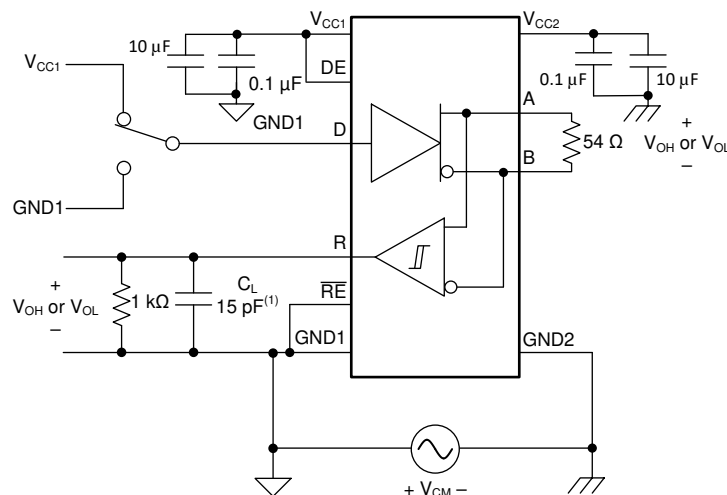
(1)  $R_L = 100\ \Omega$  for RS422,  $R_L = 54\ \Omega$  for RS-485

图 20. Driver Voltages



(1)  $C_L$  includes fixture and instrumentation capacitance.

图 21. Driver Switching Specifications

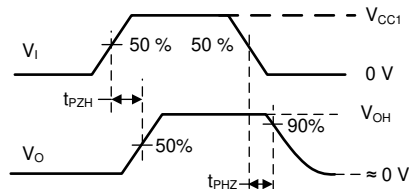
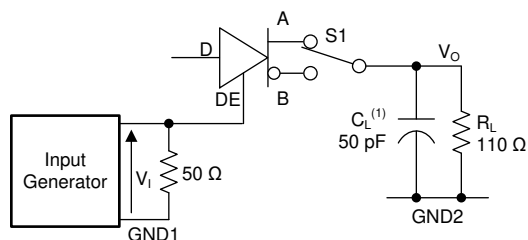


(1) Includes probe and fixture capacitance.

图 22. Common Mode Transient Immunity (CMTI)—Half Duplex



## Parameter Measurement Information (continued)



(1)  $C_L$  includes fixture and instrumentation capacitance

FIG 23. Driver Enable and Disable Times

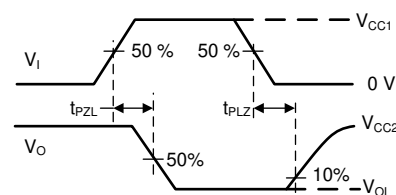
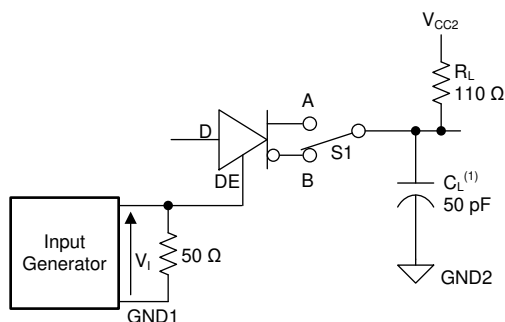
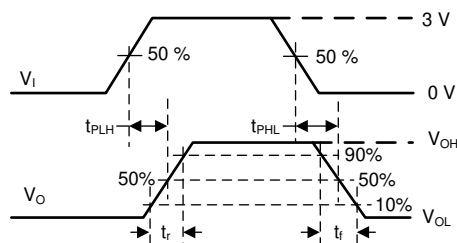
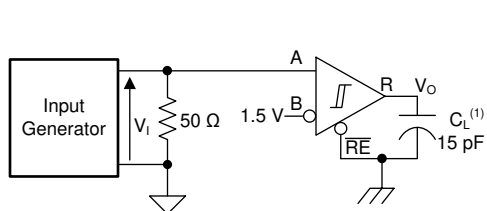


FIG 24. Driver Enable and Disable Times



(1)  $C_L$  includes fixture and instrumentation capacitance.

FIG 25. Receiver Switching Specifications

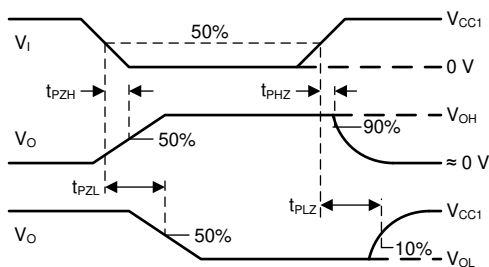


FIG 26. Receiver Enable and Disable Times

## Parameter Measurement Information (continued)

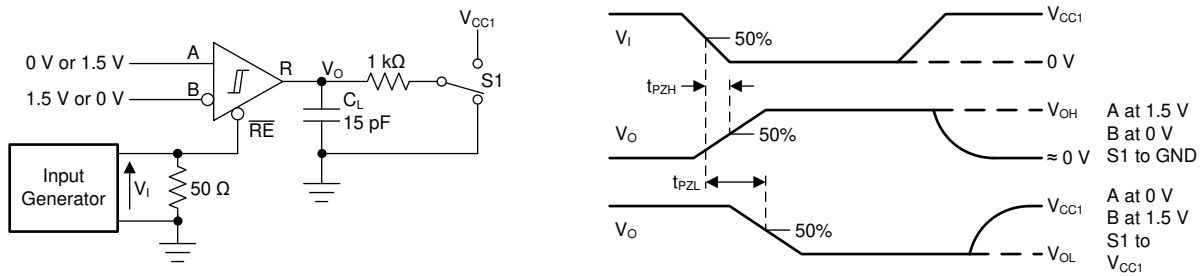
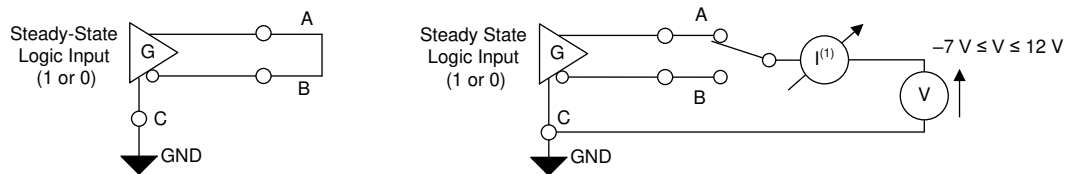


Figure 27. Receiver Enable and Disable Times



(1) The driver should not sustain any damage with this configuration.

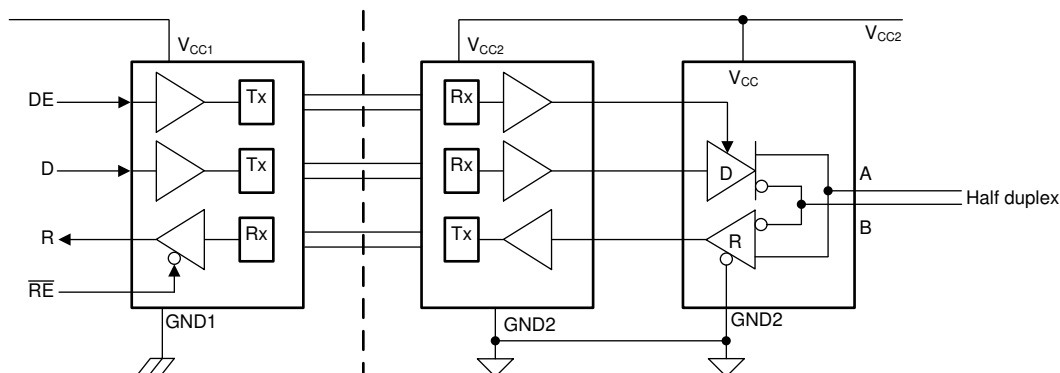
Figure 28. Short-Circuit Current Limiting

## 9 Detailed Description

### 9.1 Overview

The ISO1500 device is an isolated RS-485/RS-422 transceiver designed to operate in harsh industrial environments. This device supports data transmissions up to 1 Mbps. The ISO1500 device has a 3-channel digital isolator and an RS-485 transceiver in an ultra-small SSOP package. The silicon-dioxide based capacitive isolation barrier supports an isolation withstand voltage of 3 kV<sub>RMS</sub> and an isolation working voltage of 566 V<sub>PK</sub>. Isolation breaks the ground loop between the communicating nodes and lets data transfer in the presence of large ground potential differences. The wide logic supply of the device (V<sub>CC1</sub>) supports interfacing with 1.8-V, 2.5-V, 3.3-V, and 5-V control logic. [Functional Block Diagram](#) shows the functional block diagram of the the half-duplex device.

### 9.2 Functional Block Diagram



### 9.3 Feature Description

[表 1](#) shows an overview of the device features.

**表 1. Device Features**

PART NUMBER	ISOLATION	DUPLEX	DATA RATE	PACKAGE
ISO1500	Basic	Half	1 Mbps	16-pin SSOP

#### 9.3.1 Electromagnetic Compatibility (EMC) Considerations

Many applications in harsh industrial environment are sensitive to disturbances such as electrostatic discharge (ESD), electrical fast transient (EFT), surge and electromagnetic emissions. These electromagnetic disturbances are regulated by international standards such as IEC 61000-4-x and CISPR 22. Although system-level performance and reliability depends, to a large extent, on the application board design and layout, the ISO1500 device has dedicated circuitry to help protect the transceiver from Contact ESD per IEC61000-4-2.

#### 9.3.2 Failsafe Receiver

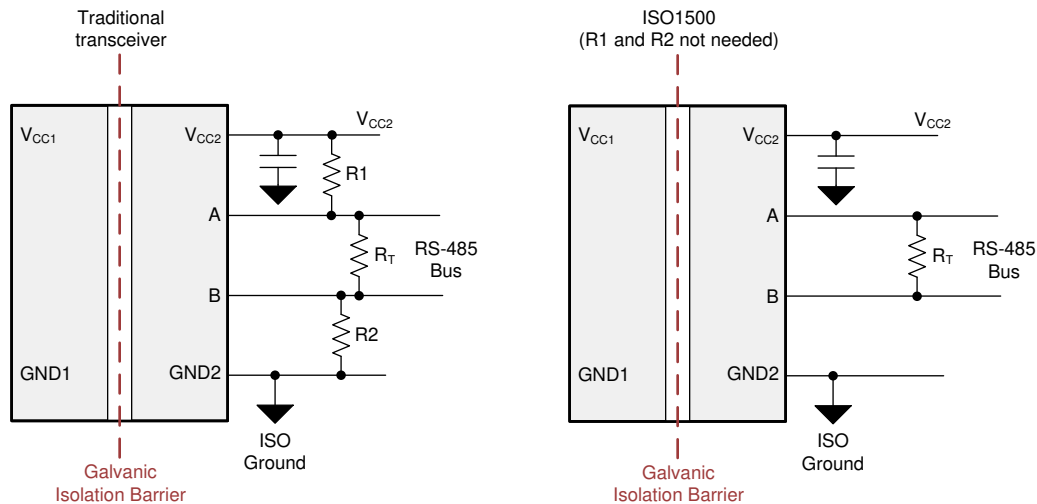
The differential receiver of the ISO1500 device has failsafe protection from invalid bus states caused by:

- Open bus conditions such as a broken cable or a disconnected connector
- Shorted bus conditions such as insulation breakdown of a cable that shorts the twisted-pair
- Idle bus conditions that occur when no driver on the bus is actively driving

The differential input of the RS-485 receiver is 0 in any of these conditions for a terminated transmission line. The receiver outputs a failsafe logic-high state so that the output of the receiver is not indeterminate.

The receiver thresholds are offset in the receiver failsafe protection so that the indeterminate range of the input does not include a 0 V differential. The receiver output must generate a logic high when the differential input ( $V_{ID}$ ) is greater than 200 mV to comply with the RS-485 standard. The receiver output must also generate a logic low when  $V_{ID}$  is less than –200 mV to comply with the RS-485 standard. The receiver parameters that determine the failsafe performance are  $V_{TH+}$ ,  $V_{TH-}$ , and  $V_{HYS}$ . Differential signals less than –200 mV always cause a low receiver output as shown in the *Electrical Characteristics* table. Differential signals greater than 200 mV always cause a high receiver output. A differential input signal that is near zero is still greater than the  $V_{TH+}$  threshold which makes the receiver output logic high. The receiver output goes to a low state only when the differential input decreases by  $V_{HYS}$  to less than  $V_{TH+}$ .

The internal failsafe biasing feature removes the need for the two external resistors that are typically required with traditional isolated RS-485 transceivers as shown in [Figure 29](#).



**Figure 29. Failsafe Transceiver**

### 9.3.3 Thermal Shutdown

The ISO1500 device has a thermal shutdown circuit to protect against damage when a fault condition occurs. A driver output short circuit or bus contention condition can cause the driver current to increase significantly which increases the power dissipation inside the device. An increase in the die temperature is monitored and the device is disabled when the die temperature becomes 170°C (typical) which lets the device decrease the temperature. The device is enabled when the junction temperature becomes 163°C (typical).

### 9.3.4 Glitch-Free Power Up and Power Down

Communication on the bus that already exist between a master node and slave node in an RS485 network must not be disturbed when a new node is swapped in or out of the network. No glitches on the bus occur when the device is:

- Hot plugged into the network in an unpowered state
- Hot plugged into the network in a powered state and disabled state
- Powered up or powered down in a disabled state when already connected to the bus

The ISO1500 device does not cause any false data toggling on the bus when powered up or powered down in a disabled state with supply ramp rates from 100  $\mu$ s to 10 ms.

## 9.4 Device Functional Modes

表 2 shows the driver functional modes.

表 2. Driver Functional Table<sup>(1)</sup>

V <sub>CC1</sub>	V <sub>CC2</sub>	INPUT D	DRIVER ENABLE DE	OUTPUTS	
				A	B
PU	PU	H	H	H	L
		L	H	L	H
		X	L	Hi-Z	Hi-Z
		X	Open	Hi-Z	Hi-Z
		Open	H	H	L
PD <sup>(2)</sup>	PU	X	X	Hi-Z	Hi-Z
X	PD	X	X	Hi-Z	Hi-Z

(1) PU = Powered Up; PD = Powered Down; H = High Level; L = Low level; X = Irrelevant, Hi-Z = High impedance state

(2) A strongly driven input signal can weakly power the floating V<sub>CC1</sub> through an internal protection diode and cause an undetermined output.

When the driver enable pin, DE, is logic high, the differential outputs, A and B, follow the logic states at data input, D. A logic high at the D input causes the A output to go high and the B output to go low. Therefore the differential output voltage defined by 式 1 is positive.

$$V_{OD} = V_A - V_B \quad (1)$$

A logic low at the D input causes the B output to go high and the A output to go low. Therefore the differential output voltage defined by 式 1 is negative. A logic low at the DE input causes both outputs to go to the high-impedance (Hi-Z) state. The logic state at the D pin is irrelevant when the DE input is logic low. The DE pin has an internal pulldown resistor to ground. The driver is disabled (bus outputs are in the Hi-Z) by default when the DE pin is left open. The D pin has an internal pullup resistor. The A output goes high and the B output goes low when the D pin is left open while the driver enabled.

表 3 shows the receiver functional modes.

表 3. Receiver Functional Table<sup>(1)</sup>

V <sub>CC1</sub>	V <sub>CC2</sub>	DIFFERENTIAL INPUT	RECEIVER ENABLE $\overline{RE}$	OUTPUT R
		$V_{ID} = V_A - V_B$		
PU	PU	$-0.02 \text{ V} \leq V_{ID}$	L	H
		$-0.2 \text{ V} < V_{ID} < 0.02 \text{ V}$	L	Indeterminate
		$V_{ID} \leq -0.2 \text{ V}$	L	L
		X	H	Hi-Z
		X	Open	Hi-Z
		Open, Short, Idle	L	H
PD <sup>(2)</sup>	PU	X	X	Hi-Z
PU	PD	X	L	H
PD <sup>(2)</sup>	PD	X	X	Hi-Z

(1) PU = Powered Up; PD = Powered Down; H = Logic High; L = Logic Low; X = Irrelevant, Hi-Z = High Impedance (OFF) state

(2) A strongly driven input signal can weakly power the floating V<sub>CC1</sub> through an internal protection diode and cause an undetermined output.

The receiver is enabled when the receiver enable pin,  $\overline{RE}$ , is logic low. The receiver output, R, goes high when the differential input voltage defined by 式 2 is greater than the positive input threshold,  $V_{TH+}$ .

$$V_{ID} = V_A - V_B \quad (2)$$

The receiver output, R, goes low when the differential input voltage defined by 式 2 is less than the negative input threshold,  $V_{TH-}$ . If the  $V_{ID}$  voltage is between the  $V_{TH+}$  and  $V_{TH-}$  thresholds, the output is indeterminate. The receiver output is in the Hi-Z state and the magnitude and polarity of  $V_{ID}$  are irrelevant when the  $\overline{RE}$  pin is logic high or left open. The internal biasing of the receiver inputs causes the output to go to a failsafe-high when the transceiver is disconnected from the bus (open-circuit), the bus lines are shorted to one another (short-circuit), or the bus is not actively driven (idle bus).

#### 9.4.1 Device I/O Schematics

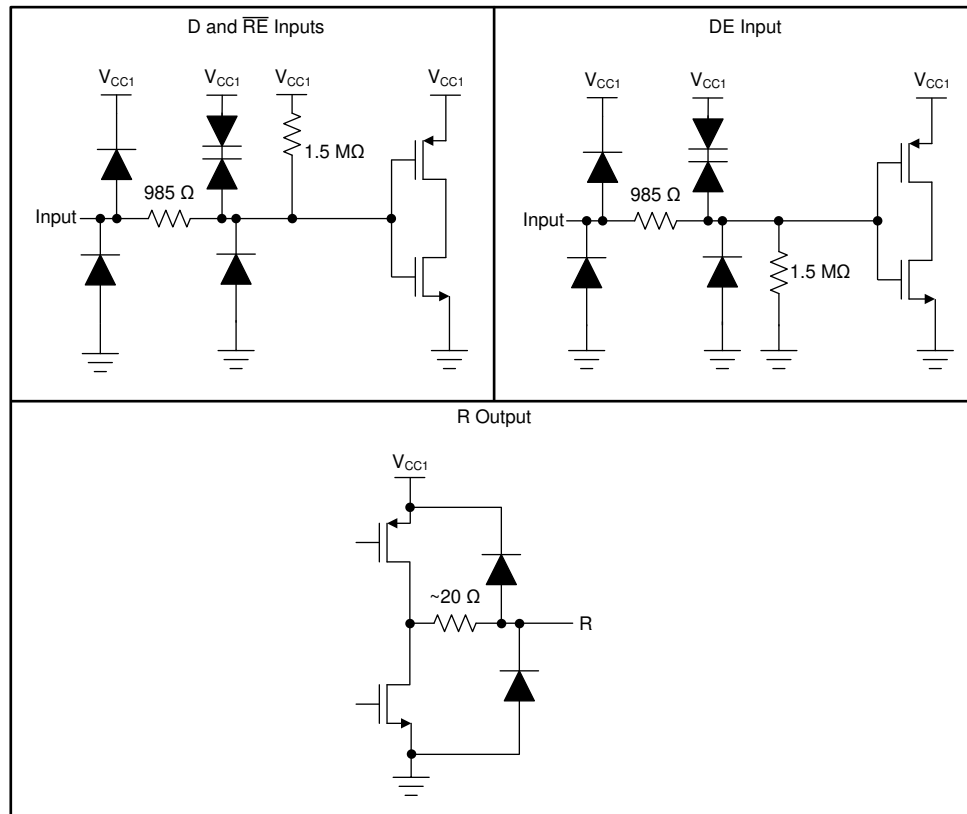


图 30. Device I/O Schematics

## 10 Application and Implementation

### 注

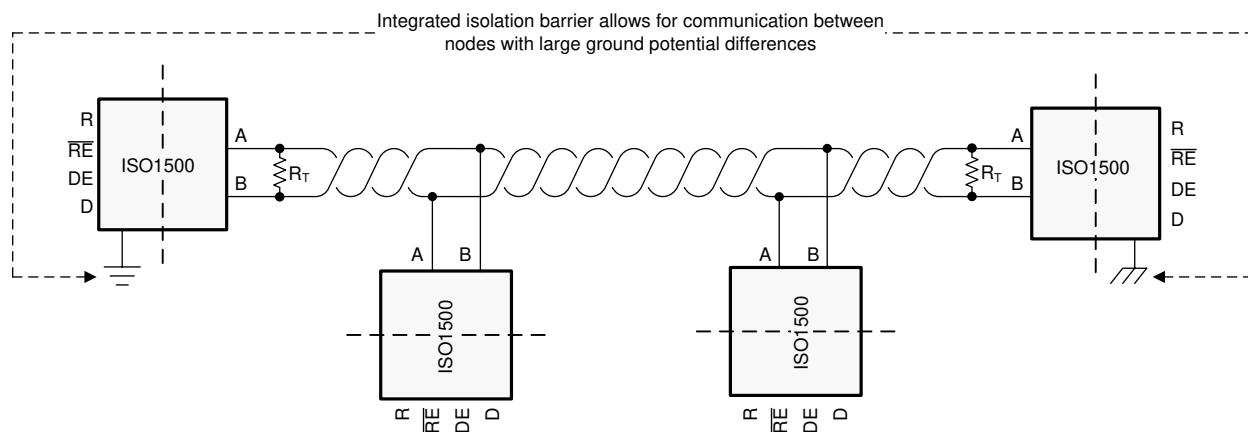
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

### 10.1 Application Information

The ISO1500 device is designed for bidirectional data transfer on multipoint RS-485 networks. The design of each RS-485 node in the network requires an ISO1500 device and an isolated power supply as shown in [Figure 32](#).

An RS-485 bus has multiple transceivers that connect in parallel to a bus cable. Both cable ends are terminated with a termination resistor,  $R_T$ , to remove line reflections. The value of  $R_T$  matches the characteristic impedance,  $Z_0$ , of the cable. This method, known as parallel termination, lets higher data rates be used over a longer cable length.

In half-duplex implementation, as shown in [Figure 31](#), the driver and receiver enable pins let any node at any given moment be configured in either transmit or receive mode which decreases cable requirements.

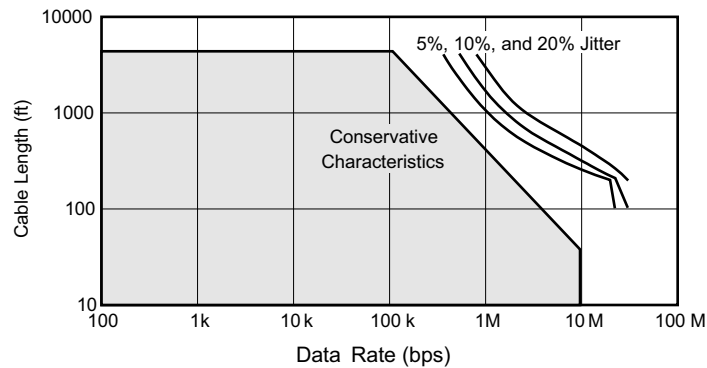


**Figure 31. Half-Duplex Network Circuit**





## Typical Application (continued)



**FIG 33. Cable Length vs Data Rate Characteristics**

Applications can increase the cable length at slower data rates compared to what is shown in FIG 33 by allowing for jitter of 5% or higher. Use FIG 33 as a guideline for cable selection, data rate, cable length and subsequent jitter budgeting.

### 10.2.2.2 Stub Length

In an RS-485 network, the distance between the transceiver inputs and the cable trunk is known as the *stub*. The stub should be as short as possible when a node is connected to the bus. Stubs are a non-terminated piece of bus line that can introduce reflections of varying phase as the length of the stub increases. The electrical length, or round-trip delay, of a stub should be less than one-tenth of the rise time of the driver as a general guideline. Therefore, the maximum physical stub length ( $L_{(STUB)}$ ) is calculated as shown in 式 3.

$$L_{(STUB)} \leq 0.1 \times t_r \times v \times c$$

where

- $t_r$  is the 10/90 rise time of the driver.
- $c$  is the speed of light ( $3 \times 10^8$  m/s).
- $v$  is the signal velocity of the cable or trace as a factor of  $c$ .

(3)

### 10.2.2.3 Bus Loading

The current supplied by the driver must supply into a load because the output of the driver depends on this current. Add transceivers to the bus to increase the total bus loading. The RS-485 standard specifies a hypothetical term of a unit load (UL) to estimate the maximum number of possible bus loads. The UL represents a load impedance of approximately 12 kΩ. Standard-compliant drivers must be able to drive 32 of these ULs.

The ISO1500 device has 1/8 UL impedance transceiver and can connect up to 256 nodes to the bus.

## 11 Power Supply Recommendations

To make sure device operation is reliable at all data rates and supply voltages, a 0.1-μF bypass capacitor is recommended at the logic and transceiver supply pins ( $V_{CC1}$  and  $V_{CC2}$ ). The capacitors should be placed as near to the supply pins as possible. Side 2 requires one  $V_{CC2}$  decoupling capacitor on each  $V_{CC2}$  pin. If only one primary-side power supply is available in an application, isolated power can be generated for the secondary-side with the help of a transformer driver such as TI's SN6505B device. For such applications, detailed power supply design and transformer selection recommendations are available in the [SN6505 Low-Noise 1-A Transformer Drivers for Isolated Power Supplies data sheet](#).

## 12 Layout

### 12.1 Layout Guidelines

A minimum of four layers is required to accomplish a low EMI PCB design (see [Figure 34](#)). Layer stacking should be in the following order (top-to-bottom): high-speed signal layer, ground plane, power plane and low-frequency signal layer.

- Routing the high-speed traces on the top layer avoids the use of vias (and the introduction of their inductances) and allows for clean interconnects between the isolator and the transmitter and receiver circuits of the data link.
- Placing a solid ground plane next to the high-speed signal layer establishes controlled impedance for transmission line interconnects and provides an excellent low-inductance path for the return current flow.
- Placing the power plane next to the ground plane creates additional high-frequency bypass capacitance of approximately 100 pF/in<sup>2</sup>.
- Routing the slower speed control signals on the bottom layer allows for greater flexibility as these signal links usually have margin to tolerate discontinuities such as vias.

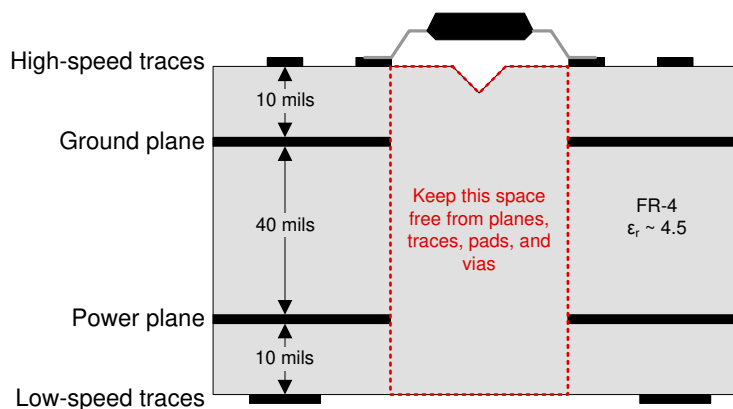
[Figure 35](#) shows the recommended placement and routing of the device bypass capacitors and optional TVS diodes. Put the two  $V_{CC2}$  bypass capacitors on the top layer and as near to the device pins as possible. Do not use vias to complete the connection to the  $V_{CC2}$  and GND2 pins. If an additional supply voltage plane or signal layer is needed, add a second power or ground plane system to the stack to keep it symmetrical. This makes the stack mechanically stable and prevents it from warping. Also the power and ground plane of each power system can be placed closer together, thus increasing the high-frequency bypass capacitance significantly.

Refer to the [Digital Isolator Design Guide](#) for detailed layout recommendations.

#### 12.1.1 PCB Material

For digital circuit boards operating at less than 150 Mbps, (or rise and fall times greater than 1 ns), and trace lengths of up to 10 inches, use standard FR-4 UL94V-0 printed circuit board. This PCB is preferred over cheaper alternatives because of lower dielectric losses at high frequencies, less moisture absorption, greater strength and stiffness, and the self-extinguishing flammability-characteristics.

### 12.2 Layout Example



**Figure 34. Recommended Layer Stack**

## Layout Example (continued)

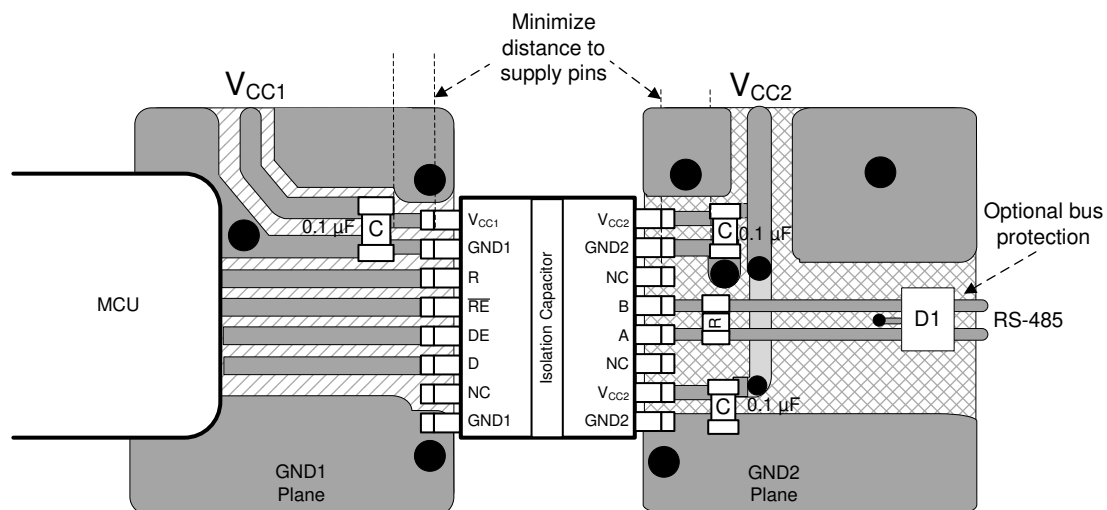


图 35. Layout Example

## 13 デバイスおよびドキュメントのサポート

### 13.1 ドキュメントのサポート

#### 13.1.1 関連資料

関連資料については、以下を参照してください。

- テキサス・インスツルメンツ、『デジタル・アイソレータ設計ガイド』
- テキサス・インスツルメンツ、『絶縁の用語集』
- テキサス・インスツルメンツ、『ISO1500絶縁型RS-485半二重評価基板』ユーザー・ガイド

### 13.2 ドキュメントの更新通知を受け取る方法

ドキュメントの更新についての通知を受け取るには、[ti.com](http://ti.com)のデバイス製品フォルダを開いてください。右上の「アラートを受け取る」をクリックして登録すると、変更されたすべての製品情報に関するダイジェストを毎週受け取れます。変更の詳細については、修正されたドキュメントに含まれている改訂履歴をご覧ください。

### 13.3 コミュニティ・リソース

TI E2E™ support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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### 13.5 静電気放電に関する注意事項



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### 13.6 Glossary

[SLYZ022](#) — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 14 メカニカル、パッケージ、および注文情報

以降のページには、メカニカル、パッケージ、および注文に関する情報が記載されています。これらの情報は、指定のデバイスに対して提供されている最新のデータです。このデータは予告なく変更されることがあり、ドキュメントが改訂される場合もあります。本データシートのブラウザ版を使用されている場合は、画面左側の説明をご覧ください。

## PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package   Pins	Package qty   Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
<a href="#">ISO1500DBQ</a>	Active	Production	SSOP (DBQ)   16	75   TUBE	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	1500
<a href="#">ISO1500DBQR</a>	Active	Production	SSOP (DBQ)   16	2500   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	1500
ISO1500DBQRG4	Active	Production	SSOP (DBQ)   16	2500   LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	1500

<sup>(1)</sup> **Status:** For more details on status, see our [product life cycle](#).

<sup>(2)</sup> **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

<sup>(3)</sup> **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

<sup>(4)</sup> **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

<sup>(6)</sup> **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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## TAPE AND REEL INFORMATION



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO1500DBQR	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO1500DBQRG4	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

## TAPE AND REEL BOX DIMENSIONS



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO1500DBQR	SSOP	DBQ	16	2500	350.0	350.0	43.0
ISO1500DBQRG4	SSOP	DBQ	16	2500	350.0	350.0	43.0

## TUBE



\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
ISO1500DBQ	DBQ	SSOP	16	75	505.46	6.76	3810	4





**DBQ0016A**

# PACKAGE OUTLINE

**SSOP - 1.75 mm max height**

SHRINK SMALL-OUTLINE PACKAGE



4214846/A 03/2014

## NOTES:

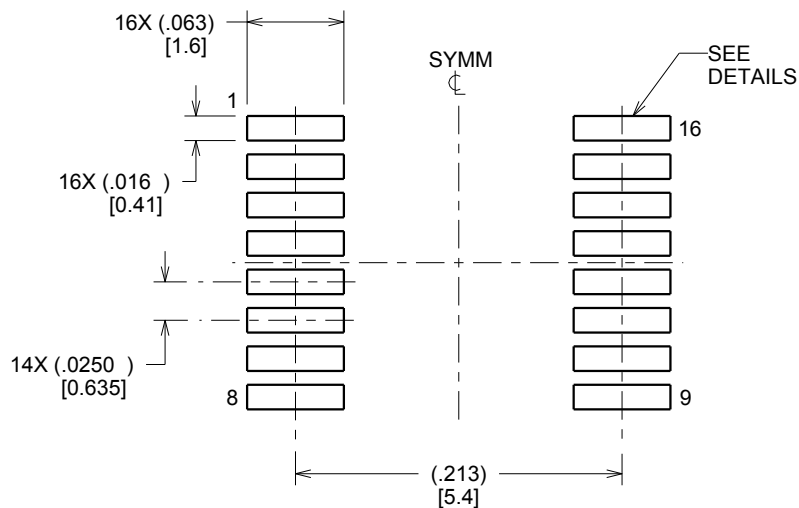
- Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
- This drawing is subject to change without notice.
- This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
- This dimension does not include interlead flash.
- Reference JEDEC registration MO-137, variation AB.

# EXAMPLE BOARD LAYOUT

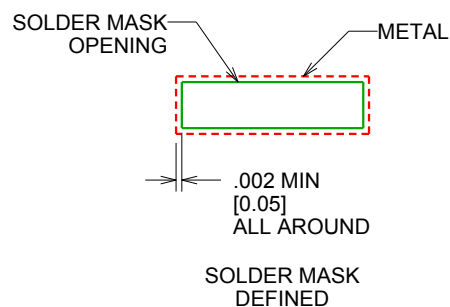
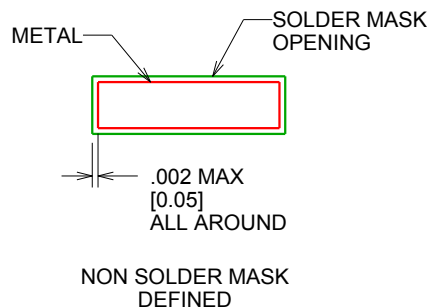
DBQ0016A

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



LAND PATTERN EXAMPLE  
SCALE:8X



SOLDER MASK DETAILS

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NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

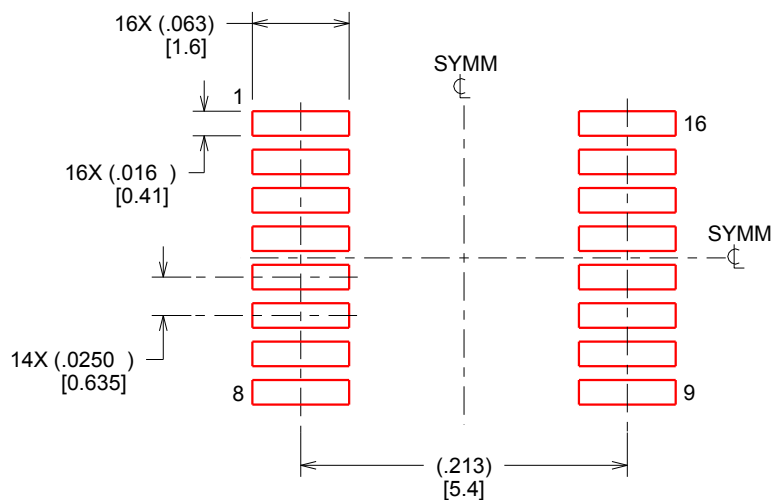
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

## EXAMPLE STENCIL DESIGN

DBQ0016A

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



SOLDER PASTE EXAMPLE  
BASED ON .005 INCH [0.127 MM] THICK STENCIL  
SCALE:8X

4214846/A 03/2014

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

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